

With Cutting-Edge Linear Motor

High-Speed, Low-Vibration, High-Accuracy Measuring



Linear Motor Drive (Patented)

- A linear motor drive ensures high accuracy and high-speed movement.
- Low vibration ensures more stable measurement at high magnifications.
- *See page 8 for the details of the linear drive.

High-Speed Measurement for Dramatically Improved Productivity

- Very high speeds of 3 mm/s maximum for roughness measurement, 20 mm/s maximum for wave measurement, and 60 mm/s for movement speed provide incredibly fast performance and better-than-ever measuring efficiency.
- Teaching and playback functions automate the entire process, from multiple location measurements to creation of the final inspection report, which can be quickly put together by pasting data into it, for measuring efficiency that is five to ten times better than other ACCRETECH instruments.

New, High-Performance Compact Pickup (Roughness)

- A new compact built-in pickup allows high-magnification, wide area measurement.
- The measurement range is 1000 µm with an outside diameter of 14 mm, and a measurement magnification of 500,000 times

- Contours of parts that normally have to be evaluated on a projector or tool microscope now can be evaluated quickly and easily.
- Measured results can be incorporated into inspection reports.

Superior ACCRETECH Functions

- Automatic Element Discrimination (Al Function)
 Elements such as points, straight lines, and circles are determined automatically without having to be specified by the operator.
- Dimension Display Actual measured values such as parameters and geometric deviation can be displayed in the measurement drawing.
- Automatic Crowning Workpiece maximum values and minimum values are detected automatically.
- Calculation Point Repeat
 - General analysis of a workpiece that includes repeating profiles can be performed by analyzing a single pattern.
- Workpiece Trace

A single manual trace can be used to determine the measuring range without setting values. This function is ideal for measuring intricate profiles.

Import and Export

Image data can be pasted into measurement results and measurement waveform data can be pasted into commercially available software files.

X ACCRETECH TOKYO SEIMITSU

SURFCOM 1900DX3/SD3

High Accuracy Analog Detector

The analog detector has simple inner structure which allows high resolution depending on measurement ranges. Low measuring force leads to less friction between a stylus and a workpiece, and the pattern of the workpiece can be faithfully incorporated. The detector resists shock and can obtain stable measurement data.



High Accuracy, Wide-Range Hybrid Detector (Option)

- SURFCOM 1900DX3/SD3 comes with a roughness detector and a contour detector as standard. A high accuracy, wide-range hybrid detector can also be added.
- Accurate, efficient measurement of workpieces with various profiles is possible.

For details about the high accuracy, wide-range hybrid detector, see SURFOCM 2000DX3/SD3 (P.14).

Roughness Pickup for Large Magnification (Option)

- A roughness measurement range of 1000 μm, enables provision of minute contour and rough alignment measurement.
- To support large magnification measurement of high-precision processed parts, magnification of up to 500,000x is provided.





Specifications

Model					SURFCOM 1900DX3/SD3							
woder				-12	-13	-14	-15	-22	-23	-24	-25	
Measuring range			50 mm									
Measuring	grange	X-axis (horizontal)		100 mm 200 mm								
	Roughness detector	Resolution		0.02 μm/1000 μm range to 0.0001 μm/6.4 μm range								
Accuracy	Contour detector	Z-axis indication accuracy (vertical)		± (1.8 + 2H /100) μm (H: Measuring height mm)								
	Contour detector	Resolution		0.1 μm/5 mm range, 0.4 μm/20 mm range, 1 μm/50 mm range								
	Roughness tracing driver	X-axis resolution		0.04 µm or 32000 points (300000 data uptake points)								
	Contour tracing driver	X-axis indication accuracy (horizontal)		± (1.0 + L/100) μm (L: Measuring length mm)								
	Contour tracing driver	Resolution		0.016 µm								
Straightness accuracy				Roughness system: (0.05 + L/1000) μm (L: Measuring length mm), Contour system: 1 μm/100 mm , 2 μm/200 mm								
X-axis (horizontal)			Linear scale									
Sensing method		Z-axis (vertical)	Differential inductance									
Column up/down sp			wn speed (Z-axis)	10 mm/s								
Speed		Measuring speed (X-axis)		0.03 mm/s to 20 mm/s								
		Moving speed (X-axis)		60 mm/s max.								
Detector	Roughness	Stylus, measuring force		Replaceable, 0.75 mN								
		Stylus radius (stylus material)		2 µmR (60° conical diamond), one piece equipped as standard								
	Contour	Stylus, measuring force		Replaceable, 10 mN to 30 mN or less, and stepless(retract) function								
		Stylus radius (stylus material)		25 μmR (24° conical carbide), two pieces equipped as standard								
		Measuring direction, position		Pull/push and Up/down directions, Max. following angle: 77°								
Operation range		Tracing driver stroke		100 mm			200 mm					
		Column up/down stroke		244 mm	444	l mm	644 mm	244 mm	444	l mm	644 mm	
Granite table		Dimensions		600 × 3	317 mm	1000 ×	450 mm	600 × 3	317 mm	1000	× 450 mm	
		Permissible loading weight ★		37 kg	28 kg	93 kg	84 kg	31 kg	22 kg	87 kg	78 kg	
Other		Installation dimensions ★	Width	1250	1250 mm 1650 mm 1250 mm		1	1650 mm				
			Depth		mm) mm) mm	-	00 mm	
			Height	1480 mm		0 mm	1880 mm			0 mm	1880 mm	
		Weight *		225 kg	235 kg	420 kg	430 kg	230 kg	240 kg	425 kg	435 kg	
		Power supply, frequency, consumption		Single phase AC 100 V ±10% (grounding required), 50 Hz/60 Hz, 670 VA								

★Dimensions and weight are for the DX type.

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